

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No. 09/521,092
Priority Filing Date March 7, 2000
Inventor Scott E. Moore et al.
Assignee Micron Technology, Inc.
Priority Group Art Unit 3723
Priority Examiner W. Berry
Attorney's Docket No. MI22-2493
Customer No. 021567
Title: Turbidity Monitoring Methods, Apparatuses, and Sensors

INFORMATION DISCLOSURE STATEMENT
PURSUANT TO 37 C.F.R. §§ 1.56, 1.97 AND 1.98

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

The listed references were cited by, or submitted to, the Office in the parent, co-pending application of the above-identified application. The above-identified application is a divisional application of co-pending application Serial No. 09/521,092, filed March 7, 2000. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned.

37 C.F.R. § 1.98(d) and MPEP § 609(2).

EL979949712


Citation of these references is respectfully requested.

Respectfully submitted,

Dated:

4/6/04

By:


James D. Shaurette
Reg. No. 39,833

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2493	PRIORITY SERIAL NO. 09/521.092	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Scott E. Moore et al.		
				PRIORITY FILING DATE March 7, 2000	PRIORITY GROUP 3723	
U.S. PATENT DOCUMENTS						
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
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	AB	6,066,030	5/2000	Uzoh		
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FOREIGN PATENT DOCUMENTS						
	Document Number	Date	Country	Class	Subclass	Translation
						Yes No
	AR					
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)						
	AS					
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2493		PRIORITY SERIAL NO. 09/521,092	
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U.S. PATENT DOCUMENTS							
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	AB						
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	AC						
	AC						
	AC						
	AE						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
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